Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/763,440	DE HAAN, WIEBE		
Examiner	Art Unit		
Vincent F. Boccio	2616		

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SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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